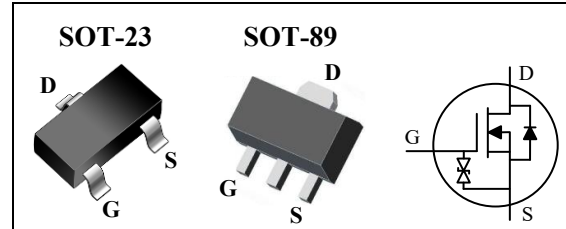


UltraVt® Depletion-Mode Power MOSFET

General Features

- ESD Improved Capability
- Depletion Mode (Normally On)
- Proprietary Advanced Planar Technology
- Proprietary Advanced Ultrahigh Vth Technology
- Optimized for SiC MOSFET Gate Drive
- High-Voltage LDO Functionality
- RoHS Compliant
- Halogen-free Available

BV_{DSX}	$V_{GS(off)}$	$I_{DSS(Min.)}$
130V	-26V to -18V	100mA



Applications

- SiC MOSFET Gate Drive Supply
- High-Voltage Auxiliary Power Supplies
- Industrial and Consumer High-Voltage LDO Applications
- Primary-Side Auxiliary Winding Regulation for Type-C / PD Fast Chargers
- Current Source
- Voltage Source

General Description

This novel depletion mode MOSFET is developed and manufactured using ARK's proprietary UltraVt® technology. It has a high threshold voltage. By using the sub threshold characteristics, the depletion mode MOSFET can provide stably power to the load, and the voltage can be clamped to protect the load without Zener diode, and the circuit consumption is reduced. It is also optimized for SiC MOSFET gate drive, providing 18V~20V output for fast chargers.

Ordering Information

Part Number	Package	Marking	Remark
DMZ1318E	SOT-23	1318	Halogen Free
DMX1318E	SOT-89	1318	Halogen Free

Absolute Maximum Ratings

$T_A = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	DMZ1318E	DMX1318E	Unit
V_{DSX}	Drain-to-Source Voltage ^[1]	130		V
V_{DGX}	Drain-to-Gate Voltage ^[1]	130		V
V_{GS}	Gate-to-Source Voltage	±32		V
I_D	Continuous Drain Current ^[2]	0.1		A
I_{DM}	Pulsed Drain Current ^[3]	0.4		A
P_D	Power Dissipation ^[4]	0.5	1.0	W
T_L	Soldering Temperature Distance of 1.6mm from case for 10 seconds	300		°C
T_J & T_{STG}	Operating and Storage Temperature Range	-55 to 150		°C

Caution: Stresses beyond those listed in the "Absolute Maximum Ratings" may cause permanent damage to the device.

Thermal Characteristics

Symbol	Parameter	DMZ1318E	DMX1318E	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	250	125	°C/W

Electrical Characteristics

OFF Characteristics

 $T_A = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
BV_{DSX}	Drain-to-Source Breakdown Voltage	130	--	--	V	$V_{GS} = -32\text{V}$, $I_D = 250\mu\text{A}$
$I_{D(off)}$	Drain-to-Source Leakage Current	--	--	20	μA	$V_{DS} = 130\text{V}$, $V_{GS} = -32\text{V}$
I_{GSS}	Gate-to-Source Leakage Current	--	--	20	μA	$V_{GS} = 32\text{V}$, $V_{DS} = 0\text{V}$
		--	--	-20		$V_{GS} = -32\text{V}$, $V_{DS} = 0\text{V}$

ON Characteristics

 $T_A = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
I_{DSS}	Saturated Drain-to-Source Current	100	--	--	mA	$V_{DS}=25\text{V}$, $V_{GS}=0\text{V}$ [5]
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	--	--	30	Ω	$V_{GS} = 0\text{V}$, $I_D = 50\text{mA}$ [5]
$V_{GS(off)}$	Gate-to-Source Cut-off Voltage	-26	--	-18	V	$V_{DS} = 35\text{V}$, $I_D = 100\mu\text{A}$

Source-Drain Diode Characteristics

 $T_A = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Min	Typ.	Max.	Unit	Test Conditions
V_{SD}	Diode Forward Voltage	--	--	1.2	V	$I_{SD} = 100\text{mA}$, $V_{GS} = -32\text{V}$

NOTE:

- [1] $T_J = +25^\circ\text{C}$ to $+150^\circ\text{C}$.
- [2] $T_C = +25^\circ\text{C}$.
- [3] Repetitive rating, pulse width limited by maximum junction temperature.
- [4] $T_C = +25^\circ\text{C}$.
- [5] Pulse width $\leq 380\mu\text{s}$, duty cycle $\leq 2\%$.

Typical Application

For the deployment of SiC MOSFETs in fast charging solutions, their specific gate drive requirements must first be addressed. Unlike GaN devices, which typically operate with a gate drive voltage of 6 V to 12 V, mainstream 650 V / 1200 V SiC MOSFETs require a gate drive voltage of +18 V to +20 V. Insufficient gate drive voltage significantly increases the on-resistance of the device, leading to higher conduction losses and reduced efficiency, thereby preventing the full utilization of SiC's low on-resistance characteristics.

To meet this drive voltage requirement in practical designs, careful consideration must be given to the power supply architecture. In a typical primary-side PD fast charger, the PWM controller is usually powered by an auxiliary winding through an LDO regulator. When adopting a SiC-based solution, this LDO must satisfy two basic requirements: first, it must have sufficient voltage margin (typically above 100 V); second, its output voltage must be stably regulated above 18 V to ensure adequate driving of the SiC MOSFET.

The typical application circuit is shown in Figure 1.

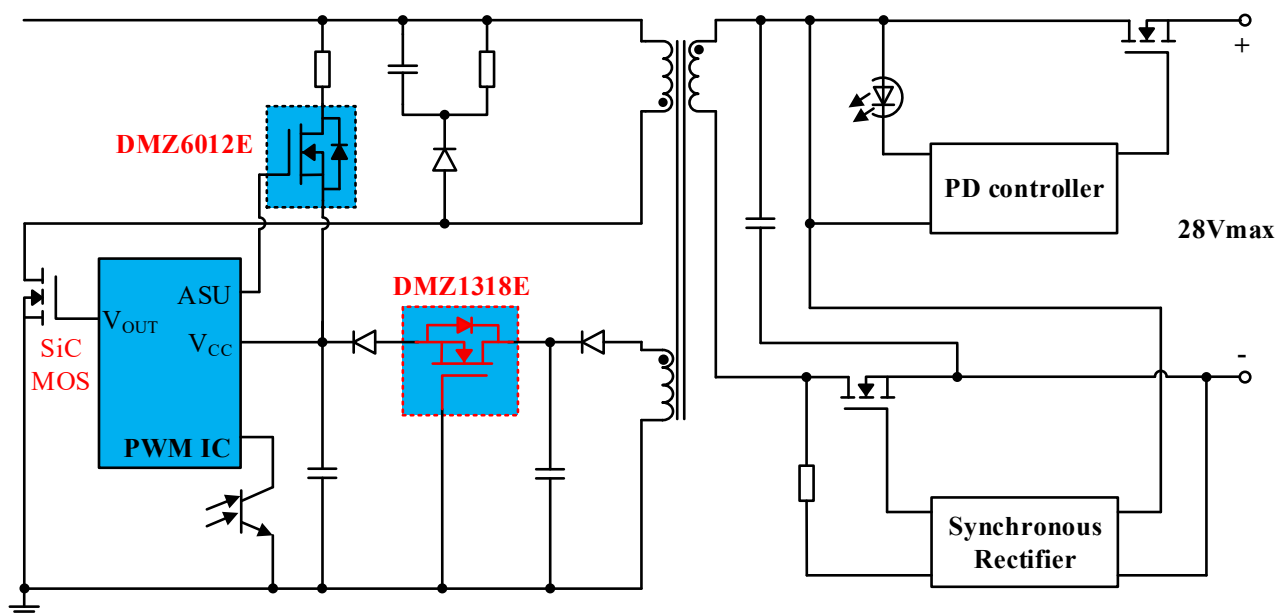


Figure 1. Type-C / PD Charger Circuit with DMZ1318E

The DMZ1318E is ideally suited for this application, providing:

Output Voltage Precisely Matches SiC Drive Window

The DMZ1318E delivers a typical output voltage of 20 V at a 5 mA load condition, with guaranteed output above 18 V. This voltage range covers the recommended gate drive voltage window (18 V to 20 V) for mainstream SiC MOSFETs, enabling full turn-on of the SiC power device and fully utilizing its low on-resistance characteristics.

Sufficient Voltage Margin

With a device voltage rating of 130 V, the DMZ1318E provides adequate margin to cope with power line fluctuations and start-up transients in PD fast charger primary-side applications, delivering stable power to the subsequent PWM IC.

Simple External Circuitry and Low Quiescent Current

As a member of the DMZ1015E/DMZ1315E series, the DMZ1318E inherits the same simple external circuit design, reliable voltage regulation characteristics, and low quiescent current. For engineers already familiar with DMZ1015E and similar devices, this minimizes repetitive design efforts when developing SiC-based solutions.

Flexible Package Options

Available in SOT-23 (ideal for compact fast charger designs) and SOT-89 (suitable for applications requiring enhanced heat dissipation) packages, the DMZ1318E accommodates the mechanical and thermal requirements of PD products across different power levels.

In addition, the DMZ1318E can also be used in power supplies employing a PFC + LLC resonant converter topology. A typical application is shown in Figure 2. The DMZ1318E provides a stable supply voltage for the AC/DC controller and half-bridge driver. Under a 5 mA load condition, the typical output voltage is 20 V, with guaranteed output above 18 V.

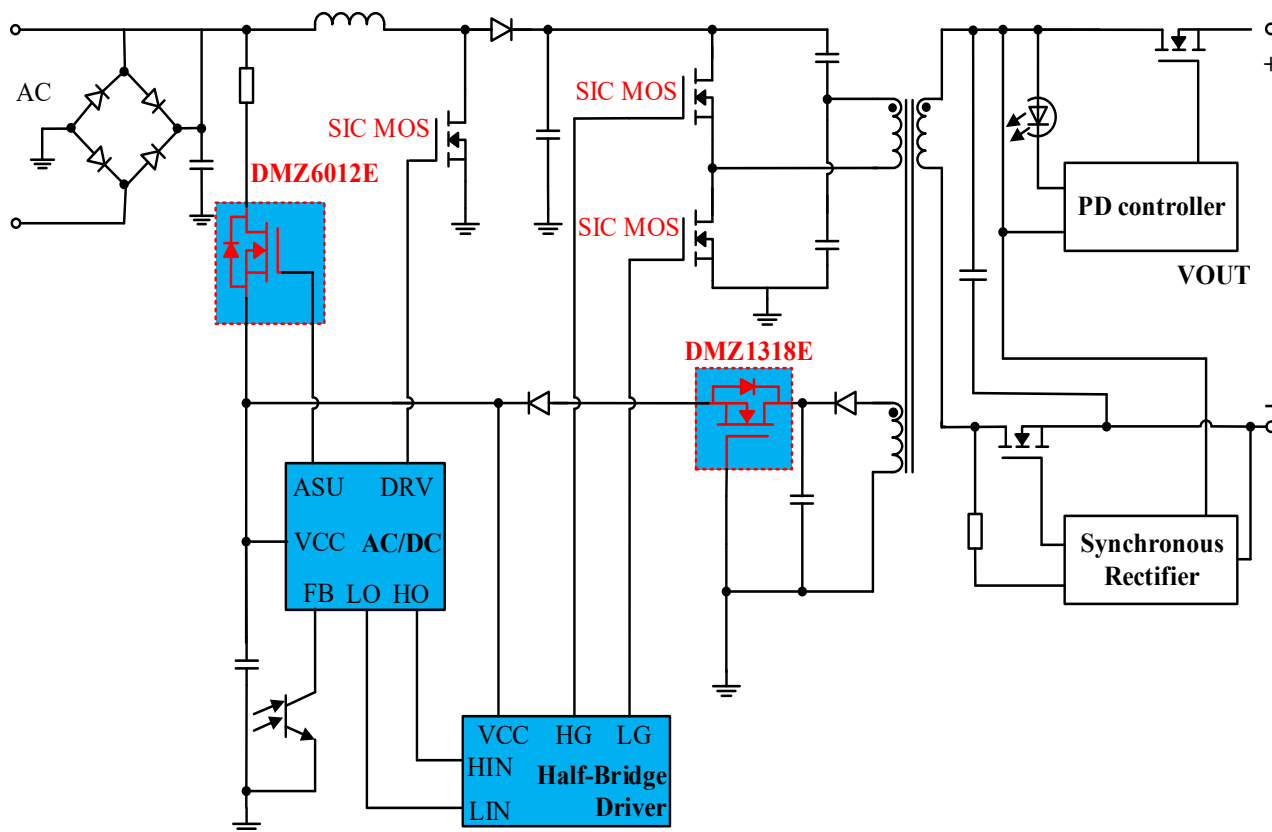


Figure 2. PFC + LLC Resonant Converter Circuit with DMZ1318E

Typical and highlight Characteristics

Figure3. Maximum Power Dissipation vs. Ambient Temperature

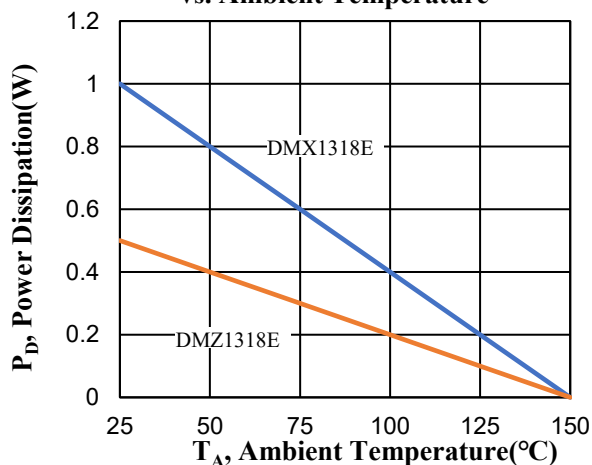
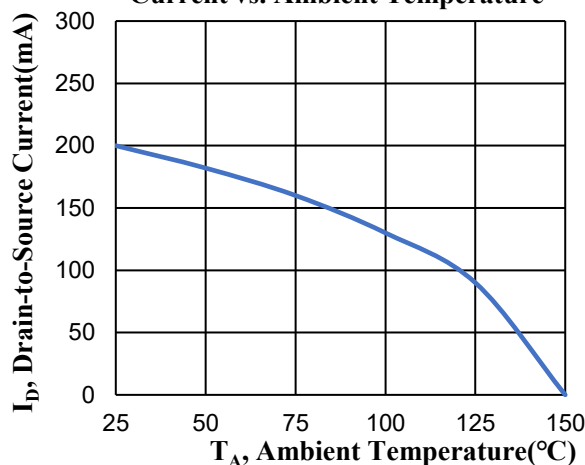


Figure4. Maximum Continuous Drain Current vs. Ambient Temperature



DMZ1318E/DMX1318E is an UltraVt® depletion mode MOS device. A stable output voltage source or current source is implemented by using the sub-threshold characteristics of the device. Its basic application is shown as Figure 5:

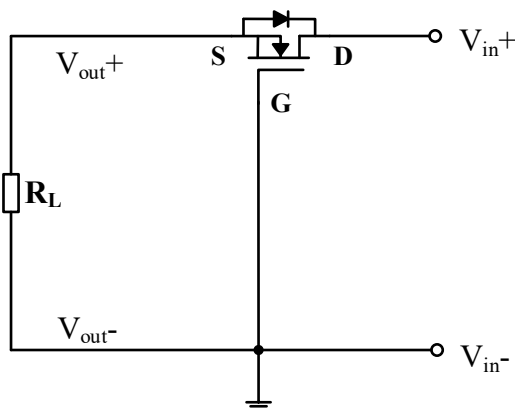


Figure5. Drain Current I_D is decided by Load Resistance

Figure 6. Clamp Voltage vs. Drain Current

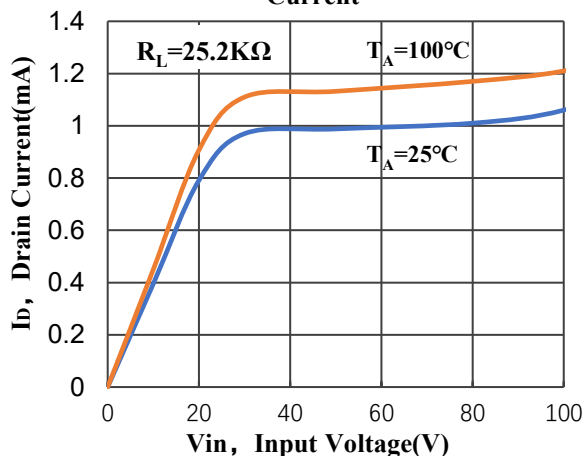
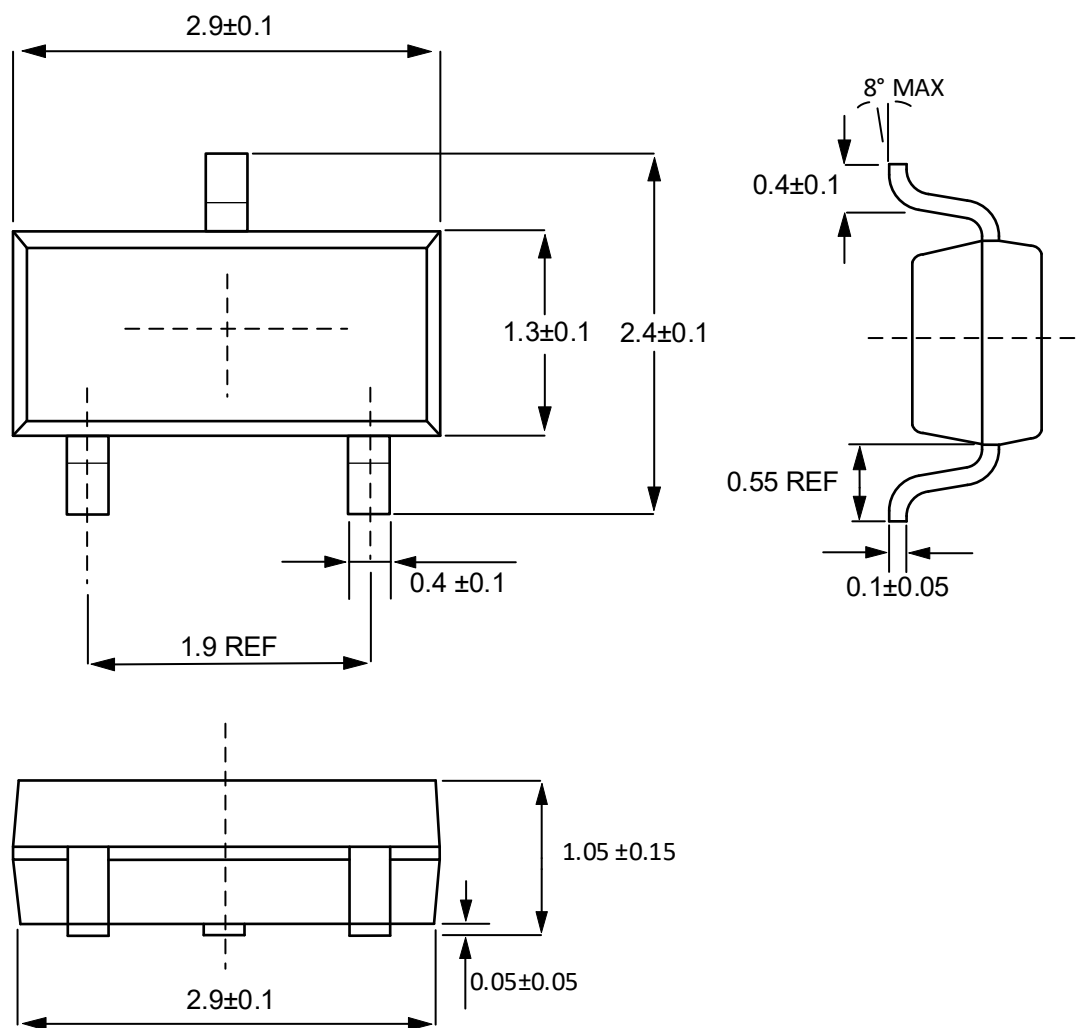


Figure6. Clamp Voltage vs. Drain Current

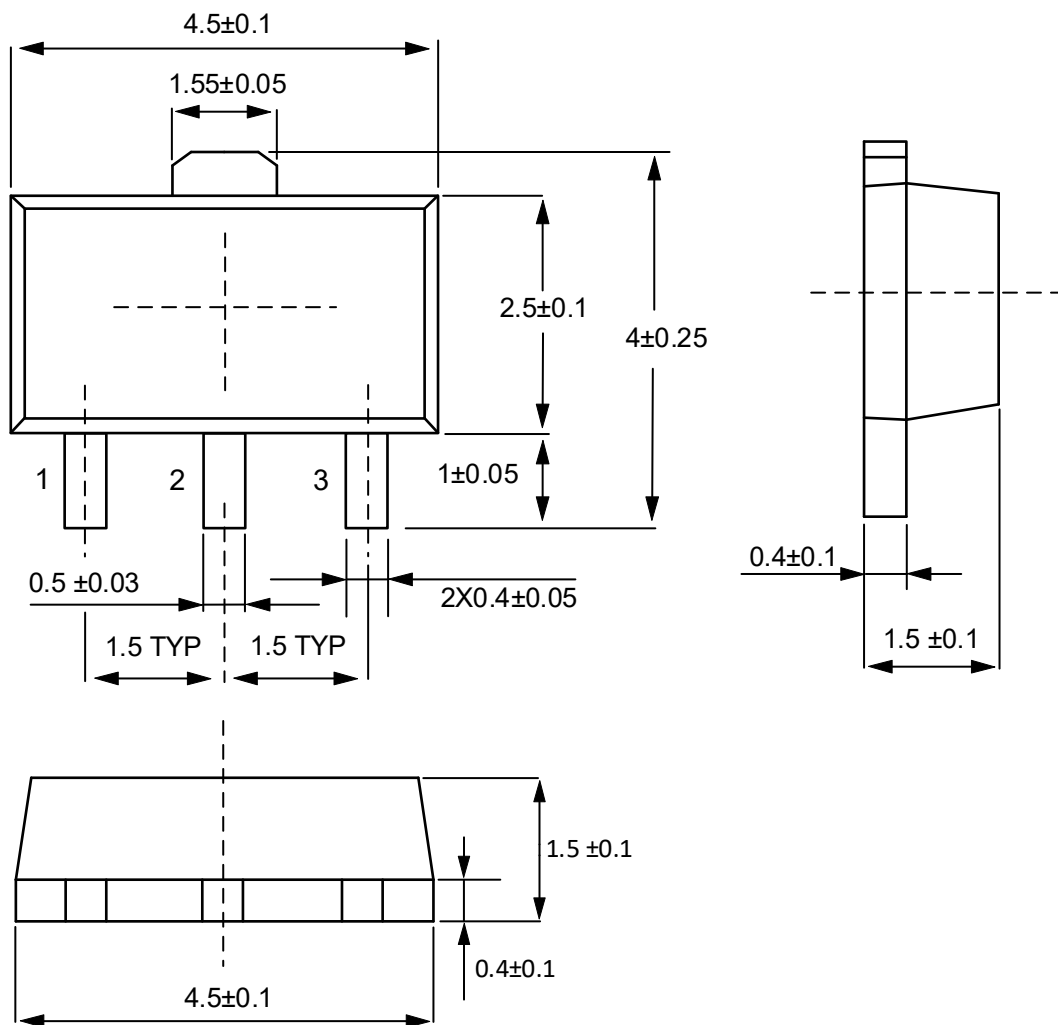
Package Dimensions

SOT-23



Unit: mm

SOT-89



Unit: mm



Published by
ARK Microelectronics Co., Ltd.
Add: D26, UESTC National Science Park, No. 1 Shuangxing Avenue, Chengdu, Sichuan
Tel: +86 (028) 8523-2215 Email: sales@ark-micro.com Website: www.ark-micro.com
All Rights Reserved.

Disclaimers

ARK Microelectronics Co., Ltd. reserves the right to make change without notice in order to improve reliability, function or design and to discontinue any product or service without notice. Customers should obtain the latest relevant information before orders and should verify that such information is current and complete. All products are sold subject to ARK Microelectronics Co., Ltd.'s terms and conditions supplied at the time of order acknowledgement.

ARK Microelectronics Co., Ltd. warrants performance of its hardware products to the specifications at the time of sale, Testing, reliability and quality control are used to the extent ARK Microelectronics Co., Ltd. deems necessary to support this warrantee. Except where agreed upon by contractual agreement, testing of all parameters of each product is not necessary performed.

ARK Microelectronics Co., Ltd. does not assume any liability arising from the use of any product or circuit designs described herein. Customers are responsible for their products and applications using ARK Microelectronics Co., Ltd.'s components. To minimize risk, customers must provide adequate design and operating safeguards.

ARK Microelectronics Co., Ltd. does not warrant or convey any license either expressed or implied under its patent rights, nor the rights of others. Reproduction of information in ARK Microelectronics Co., Ltd.'s data sheets or data books is permissible only if reproduction is without modification or alteration. Reproduction of this information with any alteration is an unfair and deceptive business practice. ARK Microelectronics Co., Ltd. is not responsible or liable for such altered documentation.

Resale of ARK Microelectronics Co., Ltd.'s products with statements different from or beyond the parameters stated by ARK Microelectronics Co., Ltd. for the product or service voids all express or implied warranties for the associated ARK Microelectronics Co., Ltd.'s product or service and is unfair and deceptive business practice. ARK Microelectronics Co., Ltd. is not responsible or liable for any such statements.

Life Support Policy:

ARK Microelectronics Co., Ltd.'s products are not authorized for use as critical components in life support devices or systems without the express written approval of ARK Microelectronics Co., Ltd.

As used herein:

1. Life support devices or systems are devices or systems which:
 - a. Are intended for surgical implant into the human body,
 - b. Support or sustain life, or
 - c. When used in accordance with instructions provided in their labeling, whose failure to perform can be reasonably expected to result in significant injury to the patient.
 2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to:
 - a. Cause the failure of the life support device or system, or
 - b. Affect its safety or effectiveness.
-